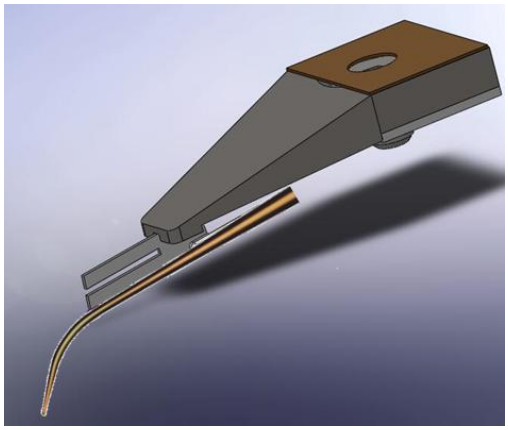
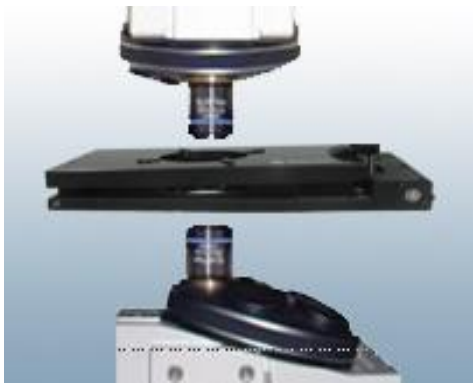
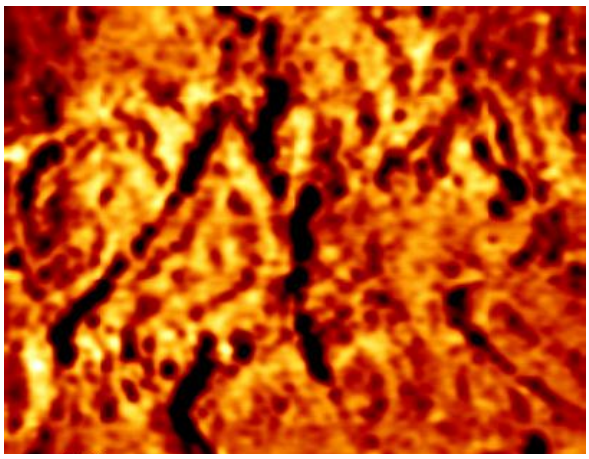
Nanonics MultiView 2000



The Most Versatile Ultrasensitive Scanning Probe Microscope





Topography of Live MDCK Cells

NANONICS IMAGING Ltd.

The Next Evolution In NanoCharacterization™

NANONICS IMAGING Ltd.

The Next Evolution In NanoCharacterization™

Ultrasensitive Compact Flexible Scanning Probe Microscope

Providing The Ultimate In Imaging & Harnessing New Horizons

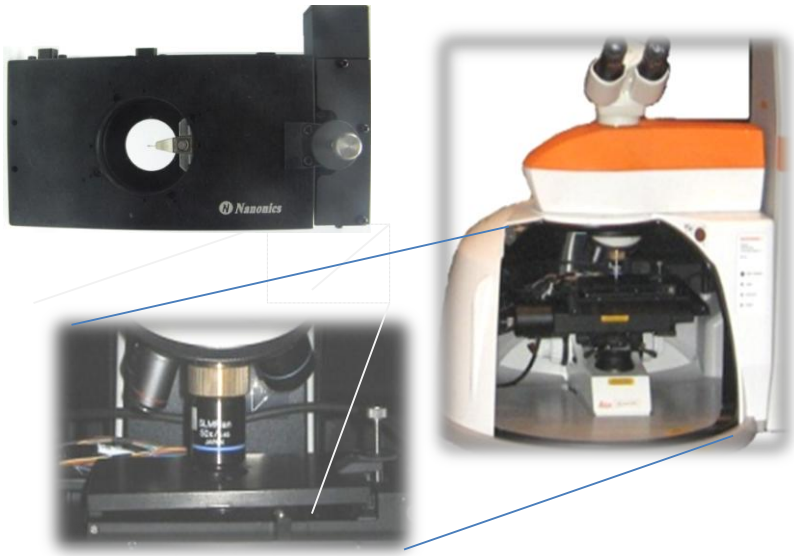
The MultiView 2000™ is a compact ultra-low noise scanning probe microscope offering the highest of quality with full flexibility. Its singular design allows for full optical integration with a variety of microscopes. For both opaque and transparent samples, the highest numerical aperture objectives can be used with working distances of <1mm. On-line sample and probe scanning is standard giving the user complete flexibility to choose whether the sample or tip is static during scanning.

Tuning forks provide the primary feedback method for such probes freeing the user from artifacts induced in electrical, optical and other imaging by often repeated laser feedback. Tuning forks are known to be the best form of SPM feedback allowing force mapping with Q factors in the thousands, even in liquid. Thus, unprecedented1.6pN force sensitivity can be achieved. For the first time, the contact point of the tip on the sample under investigation can be experimentally determined and not estimated, providing Young's moduli without error.

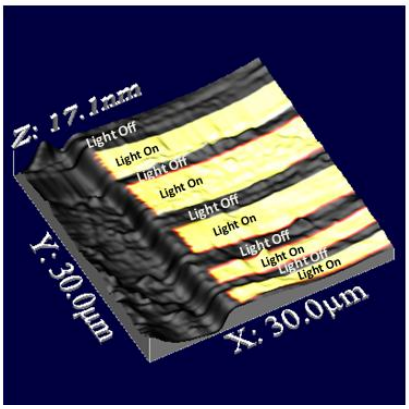
The MV2000 works with the Nanonics NanoToolKit™ of probes that cover the full spectrum of functional applications in SPM without obstructing the electron or optical axis from above or below:

- Electrical
- Thermal
- Near-field Optical (NSOM)
- Nanochemical Drawing
- Scanning Electrochemical

Whatever your needs are the MV2000 is your scanning probe microscope of choice.



Full Integration with Spectroscopy Including On-line Raman Chemical Characterization & Tip Enhanced Raman Scattering (TERS) Pioneered by Nanonics



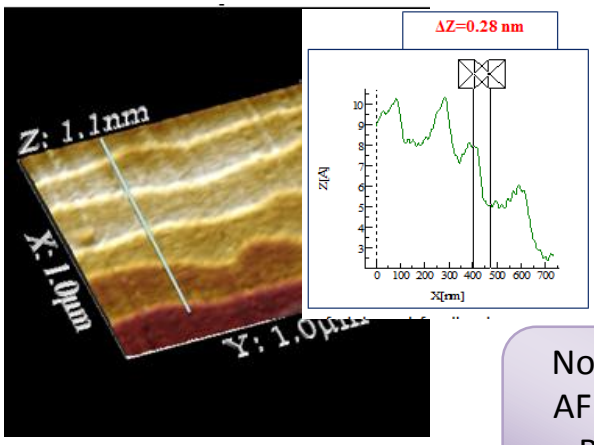
Collage of Topography & Current Imaging of a Nickel Capacitor wih 0V Bias.

Light, as in Laser Feedback, Produces a Photocurrent Artifact which is not seen In Tuning Fork Feedback

NANONICS IMAGING Ltd.

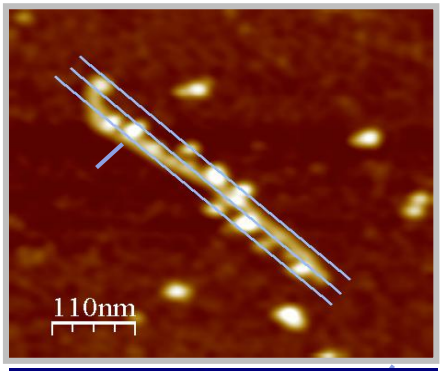
The Next Evolution In NanoCharacterization™

UltraLow Noise In X, Y And Z



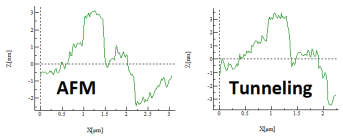
Strontium Titanate Atomic Steps

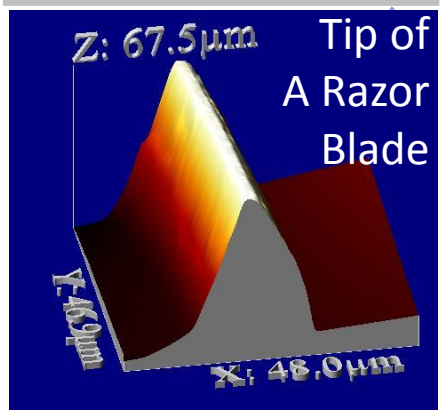
Q Dot Decorated DNA

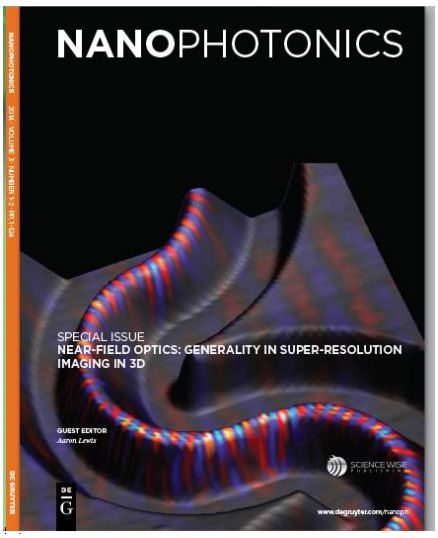


No Jump To Contact AFM Switch On-line Between AFM & Tunneling Feedback

Single HOPG Atomic Step

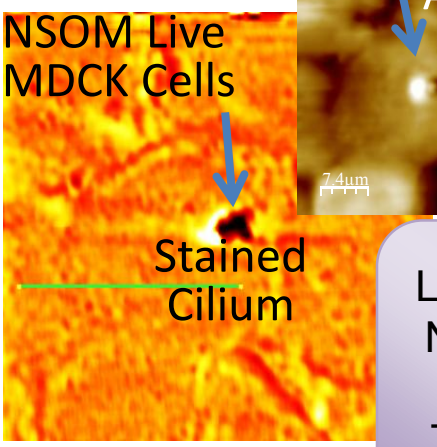


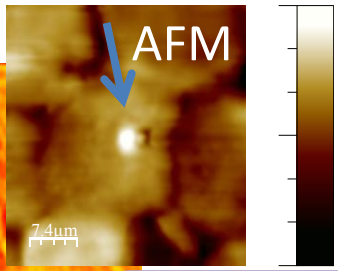




Mapping Phase & Amplitude of Propagating 1.5µm Wave In A Silicon Waveguide

Unprecedented 170µm Z Range For Studying Real Samples



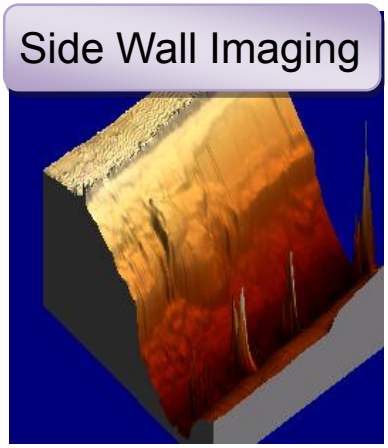


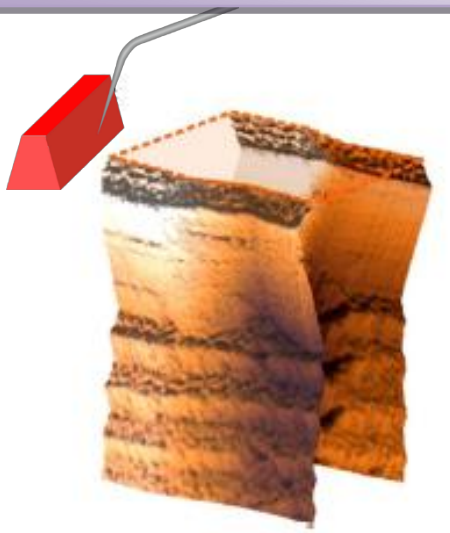
NanoPhotonics System of Choice

Live Cell NSOM Nanophotonics Possible For The First Time

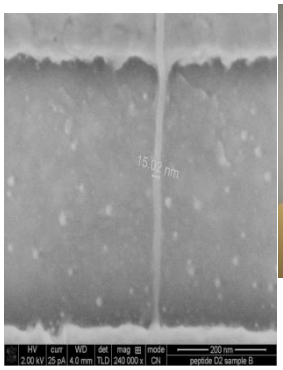
New SPM Applications Achievable With The MV 2000™

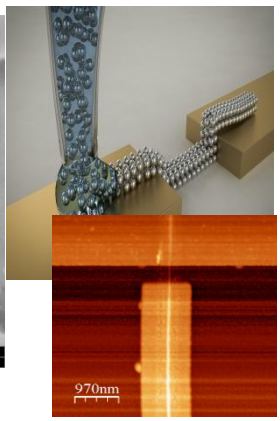
Side Wall Imaging

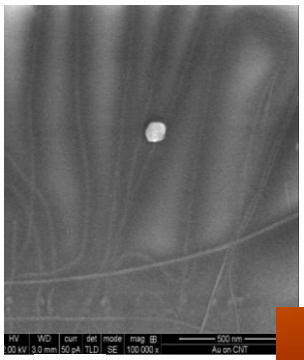




Writing Conducting Metallic Lines From Solution

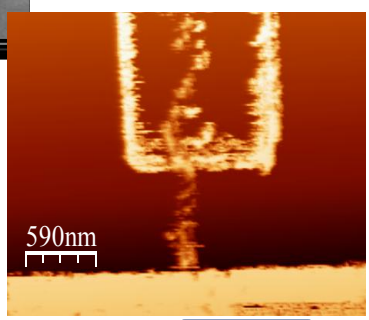


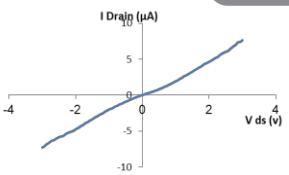


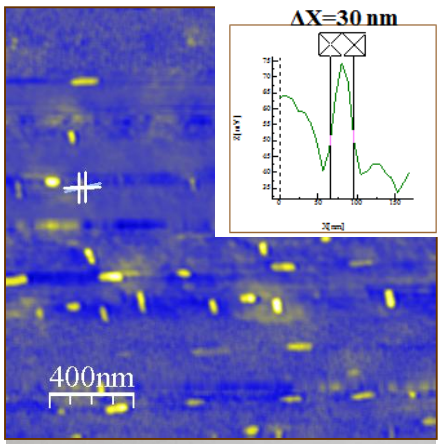


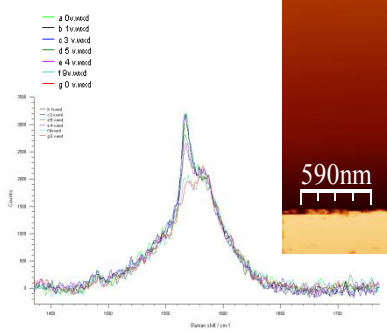
Single Nanoparticle NanoManipulated Onto A Single Carbon Nanotube

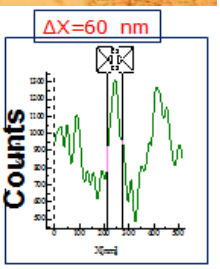
Thermal Conductivity Imaging of Voids In Silicon



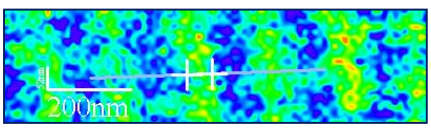




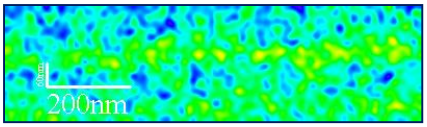


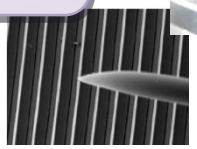


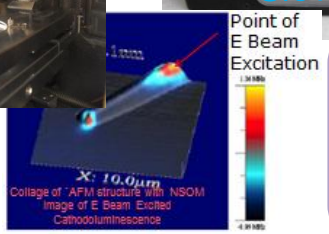
On-line Raman As A Function of Current



512cm^{-1} Strained Silicon 60 nm Grating TERS Map (Top) Far-Field Raman (Bottom)







Nanometric NSOM of Cathodo-luminescence